CLAIMS:

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1. A polymerizable silicon-containing compound having the general formula (1):

$$= \bigvee_{O} Si(CH_3)_3$$

$$= OR^1$$
(1)

wherein  $R^1$  is a hydrogen atom, halogen atom or monovalent organic group.

 A polymerizable silicon-containing ester derivative
 having an acid eliminatable substituent group according to claim 1, having the general formula (2):

$$\begin{array}{c}
-Si(CH_3)_3 \\
-OR^2
\end{array} (2)$$

wherein  $R^2$  is an acid labile group.

15 3. A polymerizable silicon-containing ester derivative having a polar group according to claim 1, having the general formula (3):

$$= \bigvee_{O} Si(CH_3)_3$$

$$= OR^3$$
(3)

wherein  $R^3$  is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group such as hydroxyl, carbonyl, ether bond or ester bond.

4. A polymerizable silicon-containing ester derivative having a silicon-containing group according to claim 1, having the general formula (4):

$$= \bigvee_{O}^{Si(CH_3)_3} (4)$$

wherein R4 is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

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5. A method for preparing a polymerizable silicon-containing compound having the general formula (B), comprising the steps of reacting an oxalate with a trimethylsilylmethyl-metal compound to form a  $\beta$ -hydroxysilyl compound having the general formula (A) and subjecting the  $\beta$ -hydroxysilyl compound to Peterson elimination reaction,

$$(H_3C)_3Si$$
  $O$   $OR$   $O$   $OR$ 

$$= \begin{array}{c} -\text{Si}(\text{CH}_3)_3 \\ -\text{OR} \end{array}$$
 (B)

wherein R stands for R<sup>1</sup>, R<sup>2</sup>, R<sup>3</sup> or R<sup>4</sup>, R<sup>1</sup> is a hydrogen atom, halogen atom or monovalent organic group, R<sup>2</sup> is an acid labile group, R<sup>3</sup> is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and R<sup>4</sup> is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

6. A polymer comprising recurring units of the general formula (la), (2a), (3a) or (4a) and having a weight average molecular weight of 2,000 to 100,000,

$$\begin{array}{c|c}
 & \text{Si}(CH_3)_3 \\
 & \leftarrow C \\
 & \rightarrow OR^1
\end{array}$$
(1a)

$$\begin{array}{c|c}
 & \text{Si(CH}_3)_3 \\
 & \text{C} & \\
 & \text{OR}^3 \\
 & \text{O}
\end{array} (3a)$$

$$\begin{array}{c}
H_2 \\
C \\
C \\
O
\end{array}$$

$$\begin{array}{c}
Si(CH_3)_3 \\
O\\
OR^4
\end{array}$$
(4a)

wherein  $R^1$  is a hydrogen atom, halogen atom or monovalent organic group,  $R^2$  is an acid labile group,  $R^3$  is a monovalent organic group of 2 to 30 carbon atoms containing an oxygen functional group, and  $R^4$  is a monovalent organic group of 3 to 30 carbon atoms containing at least one silicon atom.

7. The polymer of claim 6 further comprising recurring units of at least one type having the general formula (5a) or (6a):

$$\begin{array}{ccc}
Y^1 & Y^2 \\
+ C - C - C - \\
Y^3 & Y^4
\end{array}$$
(5a)

- wherein Y<sup>1</sup>, Y<sup>2</sup>, Y<sup>3</sup> and Y<sup>4</sup> are each independently selected from the group consisting of hydrogen, alkyl groups, aryl groups, halogen atoms, alkoxycarbonyl groups, alkoxycarbonylmethyl groups, cyano groups, fluorinated alkyl groups, and silicon atom-containing monovalent organic groups of 3 to 30 carbon atoms, any two of Y<sup>1</sup>, Y<sup>2</sup>, Y<sup>3</sup> and Y<sup>4</sup> may bond together to form a ring, Z is an oxygen atom or NR<sup>5</sup>, and R<sup>5</sup> is hydrogen, hydroxyl or alkyl.
  - 8. A resist composition comprising the polymer of claim 6.
  - 9. A chemically amplified positive resist composition comprising
    - (A) the polymer of claim 6,
    - (B) a photoacid generator, and
    - (C) an organic solvent.

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10. A method for forming a pattern, comprising the steps
of:

applying the positive resist composition of claim 9 onto an organic film on a substrate to form a coating,

prebaking the coating to form a resist film,

exposing a circuitry pattern region of the resist film to radiation.

post-exposure baking the resist film,

developing the resist film with an aqueous alkaline solution to dissolve away the exposed area, thereby forming a resist pattern, and

processing the organic film with an oxygen plasma generated by a dry etching apparatus.